Form PTO 1449 (Modified)			U.S. DEPARTMENT PATENT AND TRAI		ATTY DOCKET NO.		SERIAL NO.			
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U.S. PATENT DOCUMENTS										
EXAMINER INITIAL			DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS			
KK		AA	5,251,235	10/05/93	Bengt HENOCH					
ı		AB	5,012,075	04/30/91	Brian G. HUTCHISON, et al.					
		AC	6,315,279	11/13/01	Hayato MINAMISHIN, et al.					
		AD	4,992,648	02/12/91	Brian G. HUTCHISON					
		AE	5,458,285	10/17/95	Jerome REMIEN					
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$ \forall$	$\vdash$	AG	2003/0000957 A1	01/02/03	Dirk BREXEL, et al.			-		
KK		AH	2001/0054643 A1	12/27/01	John SIEMENS					
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K	K	AM	6-3632	01/12/94	Japan (with English Abstract)				X	
		AN	10-340364	12/22/98	Japan (with English Abstract)				×	
		AO	3-3095	01/09/91	Japan (with English Abstract)		1		x	
		AP	60-198678	10/08/85	Japan (with English Abstract)				X	
		AQ	2002-319054	10/31/02	Japan (with English Abstract)				X	
		AR	2002-319060	10/31/02	Japan (with English Abstract)				X	
	,	AS	2-297695	12/10/90	Japan (with English Abstract)				×	
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KK		AU	60-17584	01/29/85	Japan (with English Abstract)				X	
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		AY	Additional References sheet(s) attached							
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SHEET 1 OF 1

Form PTO 1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY DOCKET NO. 252008US2		SERIAL NO. 10/826,908		
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				APPLICANT				
LIST OF I	REFER	ENCES CITED BY APPL	ICANT	Kazuei YOSHIOKA, et al.				
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